

# EMC Engineering

## Top Ten EMC Problems & EMC Troubleshooting Techniques

by Kenneth Wyatt, DVD, Colorado Springs

Rev. 5, June 19, 2007



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## 1a. Ground Impedance

The overwhelming majority of high-frequency problems, whether related to emissions, immunity or self-compatibility have high ground return impedance as a root cause.

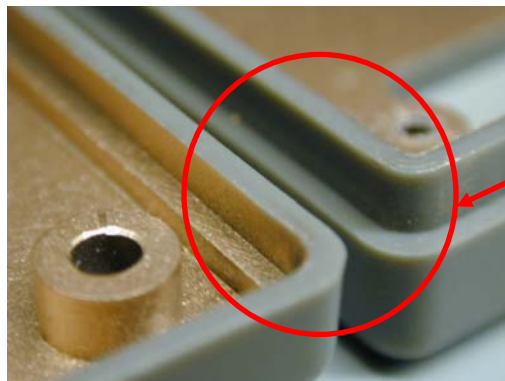
- Wires and traces have a high impedance. *This is why a ground return plane should be used at high frequencies*
- High-frequency effects start occurring at 1 MHz
- The inductance of a wire in free space is about 20 nH/inch
- A one-inch wire (or trace) has an impedance of  $2\pi f l \approx 12\Omega$  at 100 MHz



## 1b. Slot caught during a design review



## 1c. Poor shield integrity



Attempt at shielding  
module failed to  
connect halves!

Module halves copper-plated

## 2a. Poor Cable Grounding



RF Immunity problems almost always involves a cable.

➤ Shield “pigtailed” are bad – circumferential (360 degrees) are best.

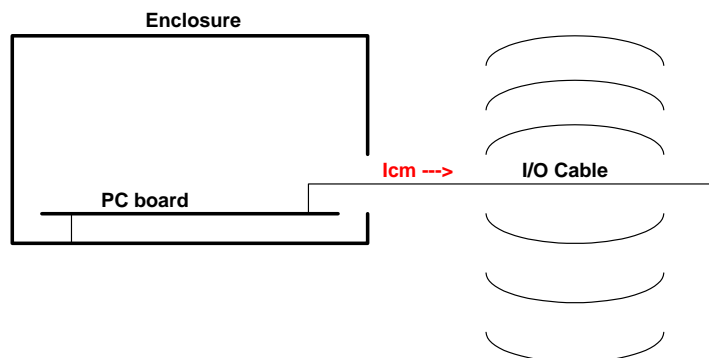


## 2b. Poor Cable Grounding (continued)

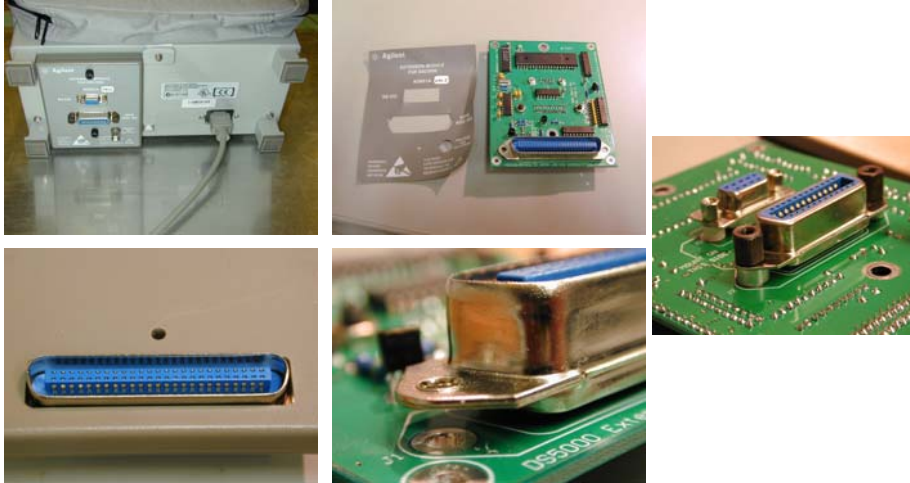
**Divert** the current back to the shielded enclosure

- Proper termination of the cable shield back to the enclosure is the key

**Block** the current with a high-impedance ferrite choke

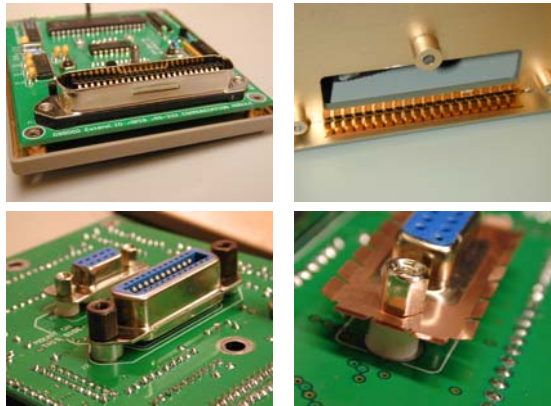


## 2c. Connector penetration through shield



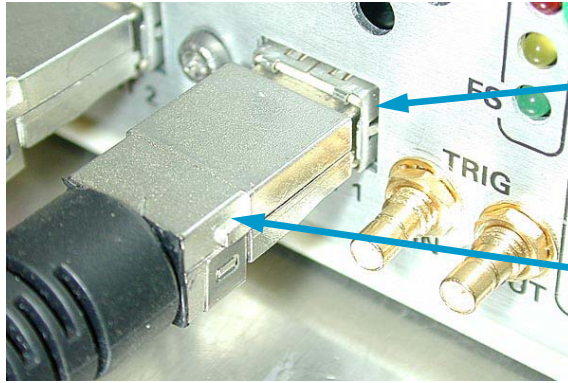
Module was unshielded, main connector ground shells had no connection with mate, connectors penetrated enclosure

## 2d. Connector penetration through shield (cont.)



Module halves copper-plated, finger stock added to connectors and ribbed main connector ground shell connects with mate

## 2e. Good Cable Grounding

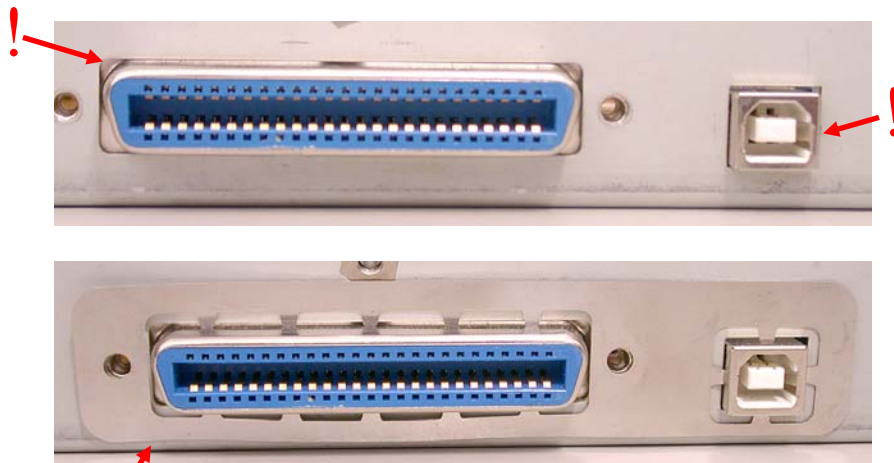


Ideal I/O connector:

- Notice the design incorporates an integrated grounding connection, which solidly connects shielded enclosure with connector ground shell in multiple locations.
- The connector ground shell then connects to the cable shield.

**Good cable grounding design – cable shield properly connected to metal enclosure.**

## 2f. Improved Cable/Connector Grounding



Shim with fingers added to shunt internal noise currents

### 3. Emissions From Switching Devices

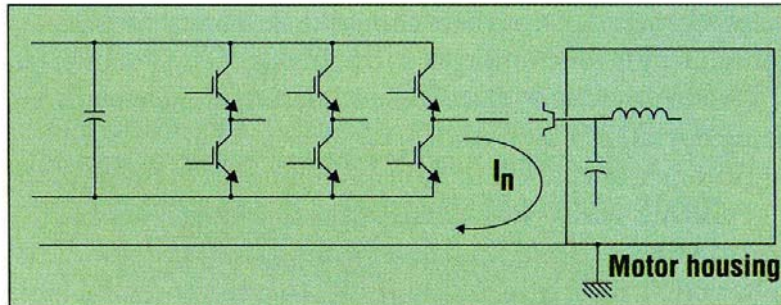


Figure 2. The switched-power noise path in a motor drive.

**Switched high-voltages couple to heat sinks and radiate**

➤ **Use bypassing and ground the heatsink (multiple points)**



### 4a. LCD Emissions

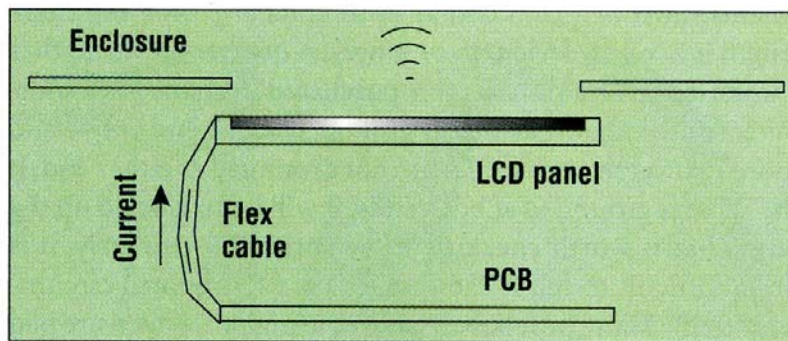


Figure 3. Emissions from an LCD.

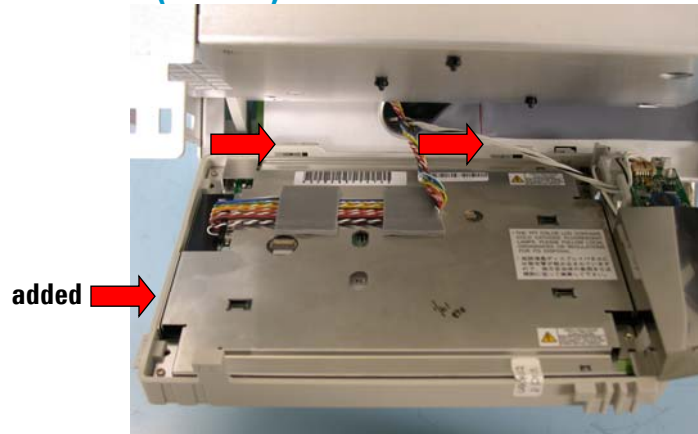
**Display cable radiates and excites the metal LCD housing**

➤ **Ground the LCD housing to the enclosure in multiple points**





## 4b. LCD Emissions (Oscar)



- > Display cable radiates and excites the metal LCD housing at the display "dot" clock frequency (437.5 MHz).
- > One more ground at the LCD housing reduced emissions 8 dB.



## 5a. Stray Internal Coupling Paths

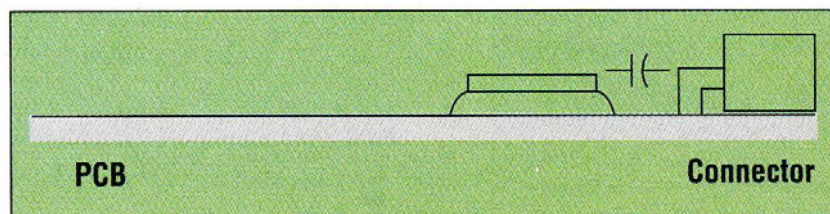
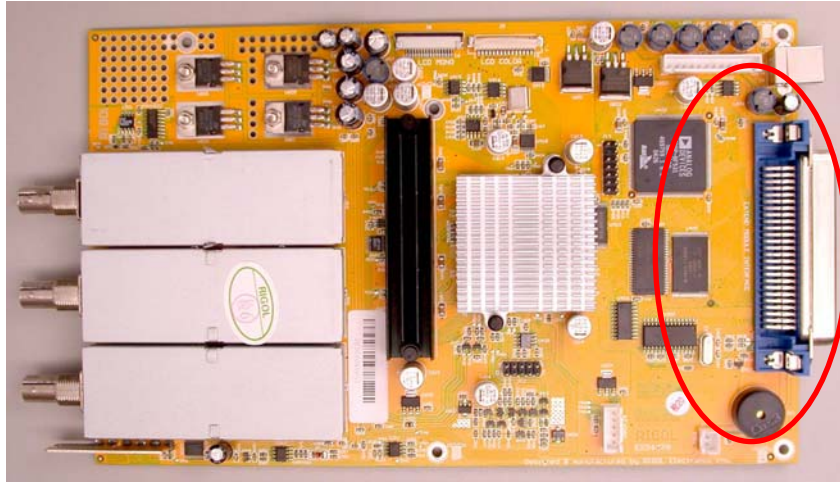


Figure 4. Stray capacitance between the chip and connector can bypass on-board filters.

- > Adding an external ferrite choke on the I/O cable often works best.
- > Interrupt the coupling path with a Faraday shield.



## DSO3000 acquisition board



Loop area on signal pins of connector coupling noisy signals.

## 5b. Data lines running underneath xtal oscillator



**Data lines couple 100 MHz (and harmonics) through I/O connector to second PC board; which in that area, is referenced to the power plane (with gaps).**



## 7a. Crosstalk

Most often due to a self-compatibility problem that occurs when noisy source currents come into close proximity to sensitive analog, or low-level digital, signals

- Route power and signals in separate cables
- Use shielded cables
- For circuit trace couplings, use additional separation or grounded "guard" traces in between the source and receptor traces

## 7b. Crosstalk in Solid Ground Planes

Crosstalk between two conductors depends on their mutual inductance and capacitance. Usually, the inductive crosstalk is dominant.

$$\text{Crosstalk} \approx \frac{K}{1 + (D/H)^2} \quad [5.2]$$

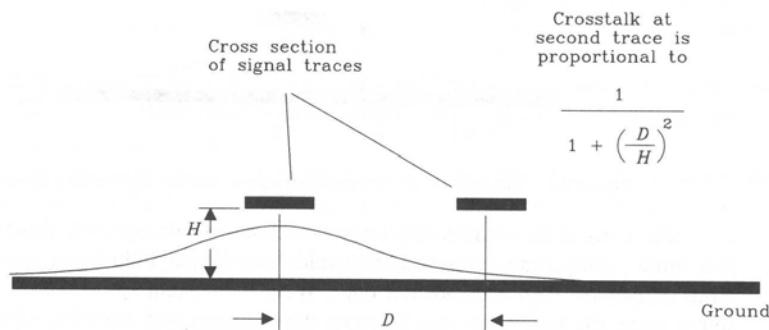
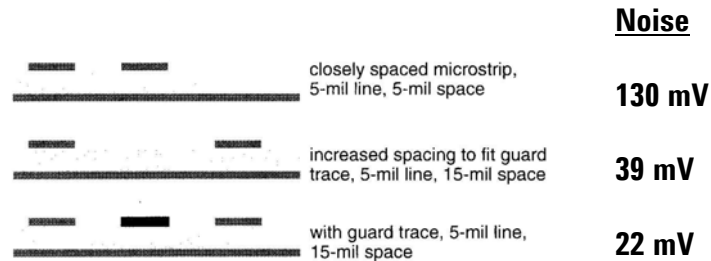


Figure 5.4 Cross section of two traces showing crosstalk.

## 7c. Reducing Crosstalk With A Guard Trace



**Figure 10-42** Three different microstrip structures evaluated for noise at the receiver of the victim line.

Ref: Signal Integrity – Simplified, Bogatin

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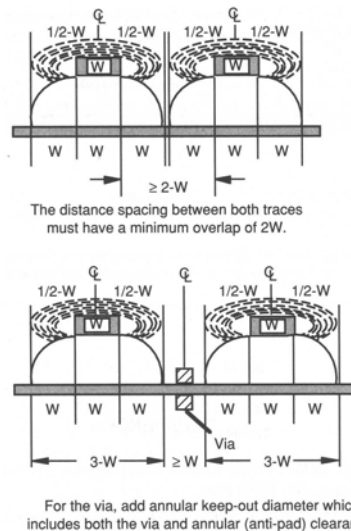
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## 7d. Use the "3W" Rule During Layout

**Clocks and periodic signals have the greatest chance of causing crosstalk in other traces.**

**Minimize crosstalk effects by using the "3W" rule; that is, ensure that all critical traces are "buffered" by at least 3 "trace-widths surrounding each potential source and victim trace.**

**Increasing the spacing from 1W to 3W will decrease far-end crosstalk by 65%.**



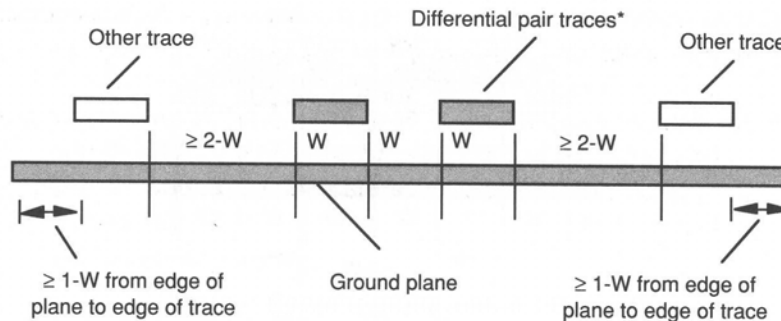
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## 7e. Differential Pairs and the "3W" Rule



\*NOTE: The "W" between the traces may require modification to adjust for the desired differential pair impedance.

Figure 7.16 Parallel differential pair routing and the 3-W rule.

**I usually consider 3-5W the minimum spacing for any critical trace to board edge spacing.**



## 8a. Inadequate Signal Returns

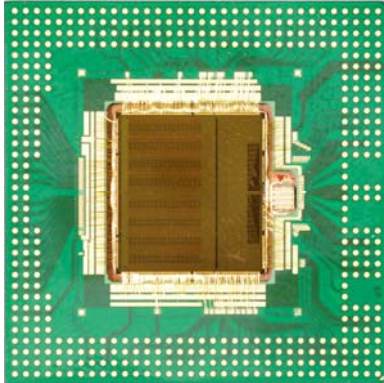
**A common situation with cables, as well as pin out designs in ASICs or other LSI devices is lack of adequate signal return wires (or pins).**

**Unless the return path impedance is zero, a fraction of the current will likely return on a stray path, creating large loop currents.**

- **Route power and signals in separate cables.**
- **Use shielded cables.**
- **Add more ground return pins to ASIC/FPGA definitions (50-50% is ideal).**



## 8b. Inadequate Signal Returns



**Ensure adequate number and position of signal return pins (approaching 50-50%).**



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## 9a. Discontinuous Return Paths

**Most PC board problems can be traced to discontinuous signal return paths. This is becoming more of an issue with increasing clock frequencies used today.**

- **Ideally, the signal travels out a trace and returns immediately under that trace**
- **All too often, the return path is broken by a discontinuity, such as a gap or slot in the ground plane or the signal trace passes through a via and changes reference planes**
- **Examine ground (and power) plane layers for gaps and slots**
- **Add extra vias for return currents when switching reference planes**

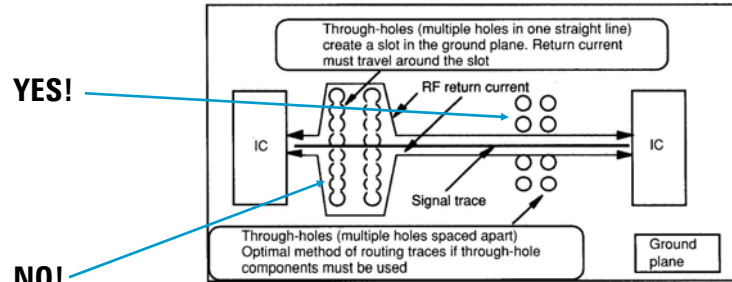
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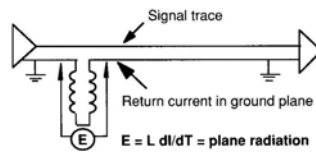
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## 9b. Generation of differential-mode emission



**DM current flows in a loop.  
The loop radiates energy.**



Equivalent circuit showing inductance in the return paths. This inductance is approximately 1 nH/cm.

Figure 4.15 Ground loops when using through-hole components (slots in the plane).

Montrose, EMC and the Printed Circuit Board, IEEE Press, 1999

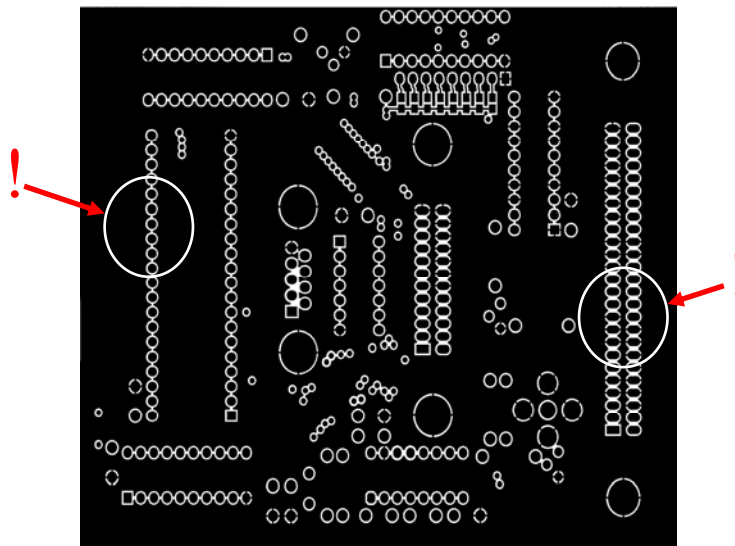
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## 9c. Discontinuous Return Paths (examples)



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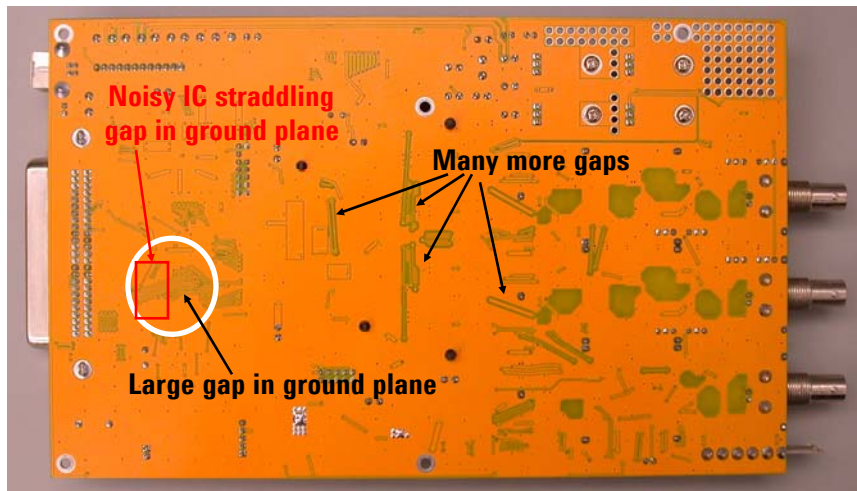


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## 9d. Slots in acquisition board signal return plane



Temporary bridge with copper tape reduced emissions 17 dB!

## 9e. Discontinuous Return Paths (examples)

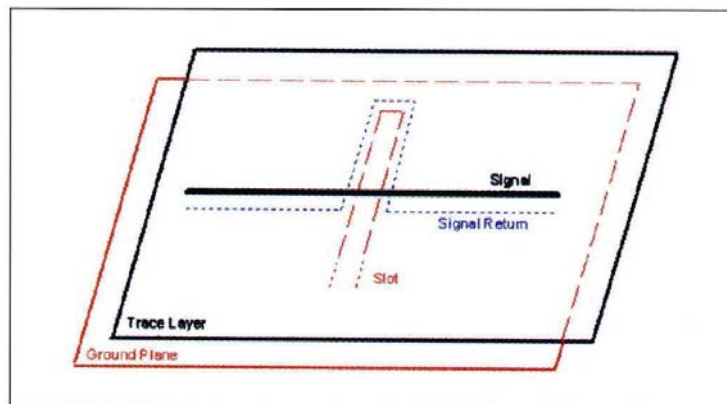


Figure 3: Routing a trace over a slot in a plane can cause a large loop area

## 9f. Discontinuous Return Paths (examples)

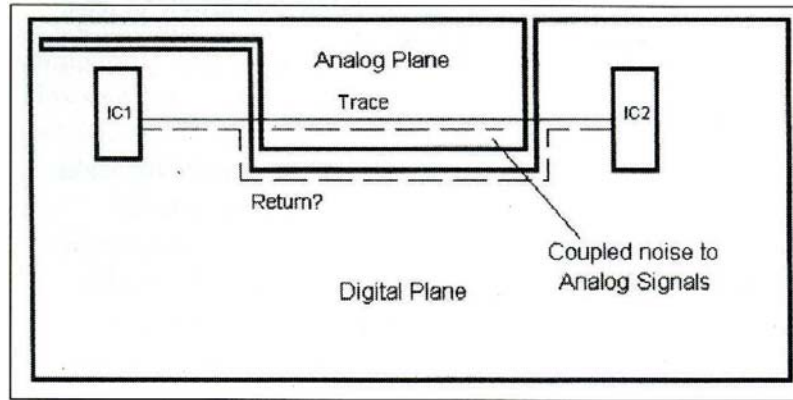
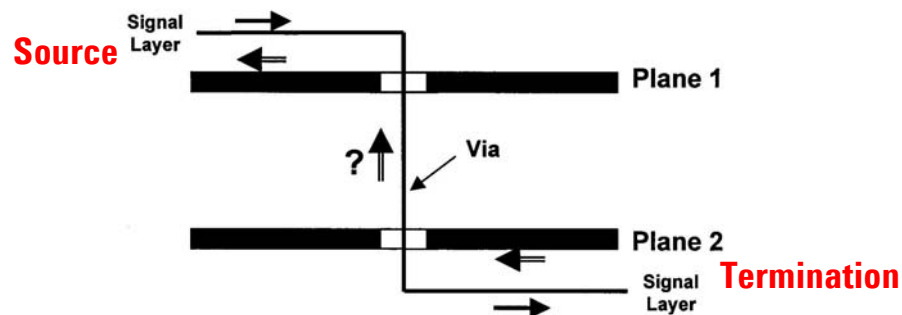


Figure 7: Routing a trace over an unrelated plane can cause several types of problems

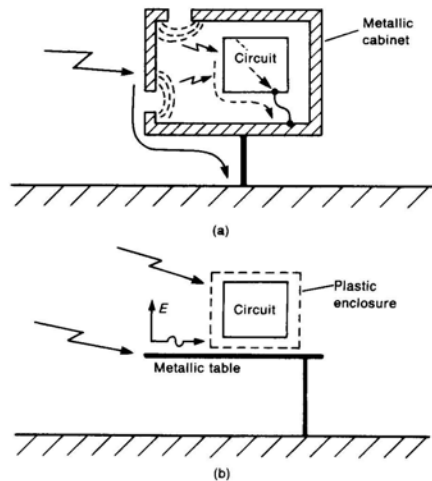
## 9g. Trace passing through two planes with via



Signal Traces Adjacent to Different Planes

**Question: where does the return signal current flow?**

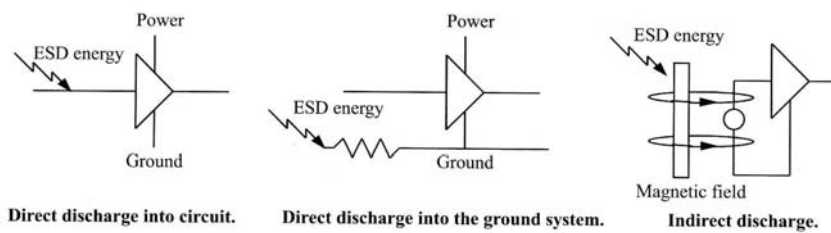
## 10a. ESD In Metal Enclosures



**FIGURE 12.3** Illustration of the coupling of an ESD discharge to an electronic circuit for (a) a metal enclosure with apertures and (b) a plastic enclosure.



## 10b. Failure Modes Caused by ESD



**Figure 2.16** Failure modes caused by an ESD event.

- Typical failure modes include a change of instrument state (front panel control), CPU reset, instrument lockup, loss of data
- Fix by shielding, rerouting cables, separation of receptor circuits



# Electromagnetic Compatibility Engineering

## EMC Pre-Compliance Testing & Troubleshooting

by Kenneth Wyatt, DVD, Colorado Springs  
Rev 3, June 19, 2007

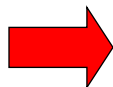


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## Five Key Threats

These comprise 95% of all EMC problems  
(EDN Magazine)

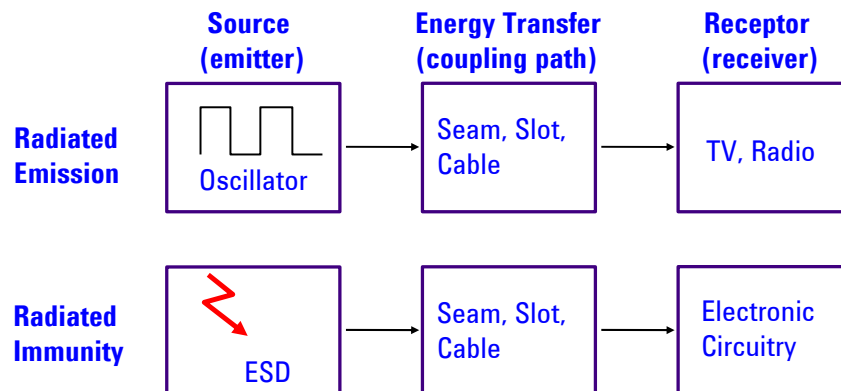
1. Radiated Emissions
2. ESD (susceptibility)
3. RF Fields (susceptibility)
4. Power disturbances
5. Internal compatibility (crosstalk, etc.)



The solution to most EMC problems is to  
***CONTROL THE PATH OF CURRENT.***



## "Source-Path-Receptor" Model



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## EMC Troubleshooting Kit



Pelican 1514 roller case  
Extra cables, adapters, etc.  
Tool kit  
DMM  
Tin can antenna  
Line filter  
Harmonic comb generator  
Ferrites  
Wrist strap

ESD meter  
Power adapters  
Spectrum Analyzer  
Sniffer probe set  
"Bow-tie" antenna  
ESD generator  
Current probe  
Broadband preamp

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## Major Contents



**Current Probe**  
FCC F-33-1



**Spectrum Analyzer**  
TTi PSA1301T

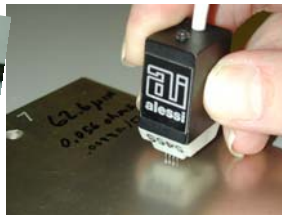


**E- and H-Field probes**  
Beehive Electronics



**Wideband Preamp**  
Mini-Circuits 2X60-3018G-S

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**Resistivity Probe**  
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**Small FRS Transmitter**

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## EMC Troubleshooting Kit

**What can you do with it?**

**The EMC troubleshooting kit may be used for the following:**

1. Identifying radiated emission sources on PC boards
2. Discovering leaky seams in enclosures
3. Measuring cable common-mode currents / radiation
4. Making quick "A-B" comparisons for proposed design changes
5. Testing for radiated and ESD immunity
6. Highly portable – may be used as a mini "EMC crash cart"

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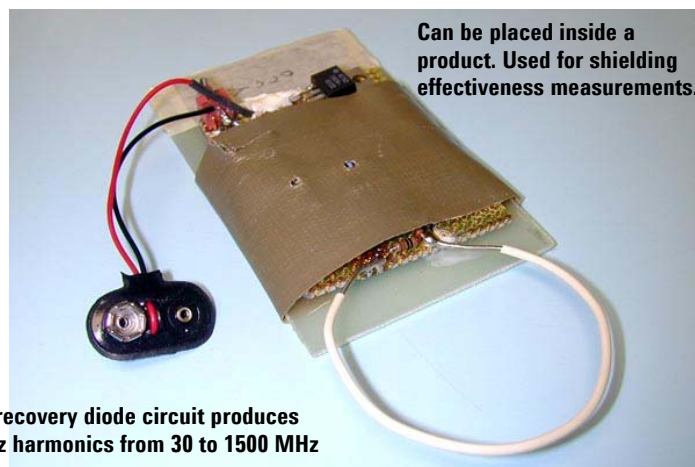
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## Simple Pre-Compliance Tests & Troubleshooting

- **Shielding tests**
- **Analyze/measure crystal oscillator harmonics**
- **E- and H-field probing**
  - PC Boards (E- and H-field probes)
  - Cables (current probes)
  - Shields (surface current and 4-point probes)
- **Measure bare PC board emissions**
- **Measure conducted emissions in cables**

## "Mini" Harmonic Comb Generator Used For Shielding Effectiveness Test

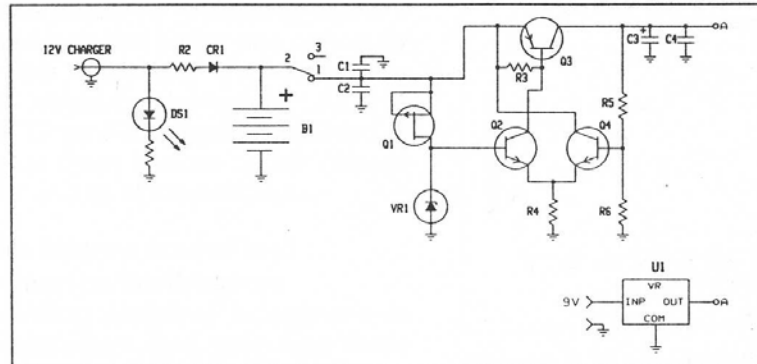


Can be placed inside a product. Used for shielding effectiveness measurements.

Step recovery diode circuit produces  
5 MHz harmonics from 30 to 1500 MHz

Wyatt/Chaney, RFI Measurements Using a Harmonic Comb Generator, RF Design Magazine, Jan. 1991

## Harmonic comb generator design



**Figure 4a. Schematic diagram of the power supply and battery charging circuit. U1 is an optional voltage regulator used for the 9V battery operated miniature comb generator.**

Wyatt/Chaney, RFI Measurements Using a Harmonic Comb Generator, RF Design Magazine, Jan. 1991

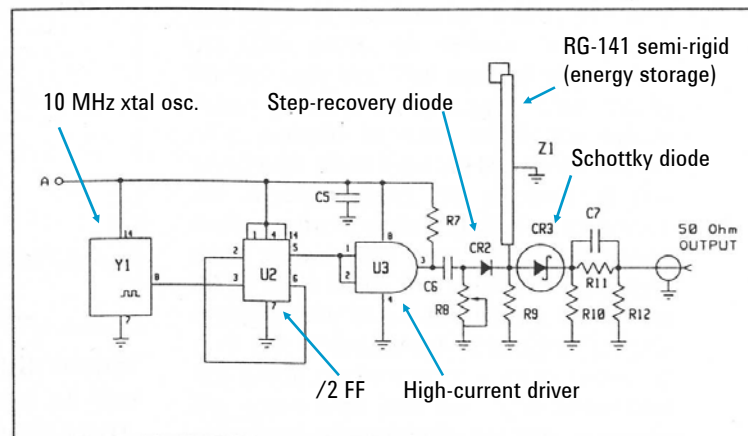
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## Harmonic comb generator design



**Figure 4b. Schematic diagram of the comb generator circuit.**

Wyatt/Chaney, RFI Measurements Using a Harmonic Comb Generator, RF Design Magazine, Jan. 1991

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# Harmonic comb generator design

Capacitors		Integrated Circuits	
C1	470 pF	U1	3-terminal 5V regulator (used only for "mini" comb generator)
C2	2.2 $\mu$ F/35V	U2	74LS74
C3	10 $\mu$ F/35V	U3	75451
C4,5	0.1 $\mu$ F		
C6	0.01 $\mu$ F		
C7	6.8 pF		
Resistors		Miscellaneous	
R1	390	B1	6V/2.6AH battery (Yuasa NP2.6-6 sealed lead acid 5.25"L x 2.375"H x 1.25"W)
R2	56/2W	S1	SPDT power switch
R3	1K	Y1	10 MHz crystal oscillator
R4,6	178	Z1	2.0' long 0.085" diameter semi-rigid coax (shorted at one end)
R5	261		
R7	23,70.5W		
R8	50 ohm trimpot		
R9,11	51.1		
R10,12	110		
Diodes			
CR1	1N4001 rectifier		
CR2	HP 5082-0180 step recovery		
CR3	HP 5082-2810 hot carrier		
DS1	LED panel light		
VR1	2.4V/400mW zener		
Transistors			
Q1	P channel JFET (select for $I_{DSS} \approx 3mA$ )		
Q2,4	2N3904		
Q3	TIP42A		

**Note:** Substitutions will have to be made for the Schottky and step-recovery diodes, as they are no longer available from HP/Agilent.

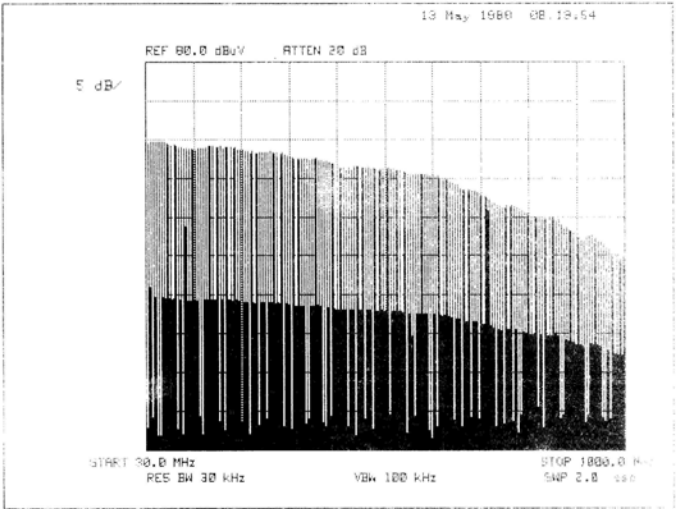
Table 1. Parts list for the comb generator.

Wyatt/Chaney, RFI Measurements Using a Harmonic Comb Generator, RF Design Magazine, Jan. 1991

# Comb generator output

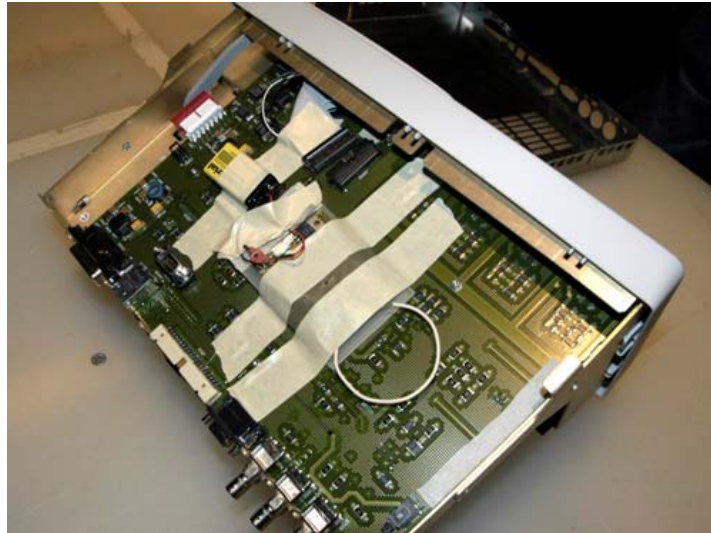
**Direct output of the harmonic comb generator into a spectrum analyzer**

**30 to 1000 MHz  
15 dB down @  
1000 MHz**



Wyatt/Chaney, RFI Measurements Using a Harmonic Comb Generator, RF Design Magazine, Jan. 1991

## Comb Generator Taped To Prototype Product

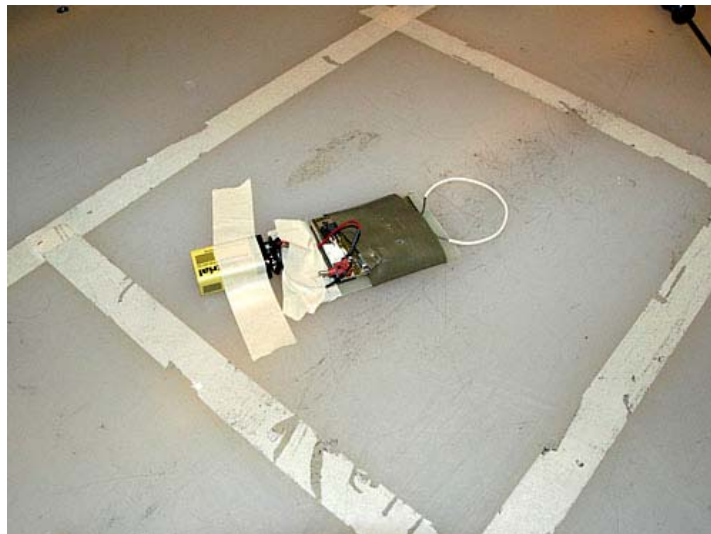


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## Then Comb Generator Is Measured Alone



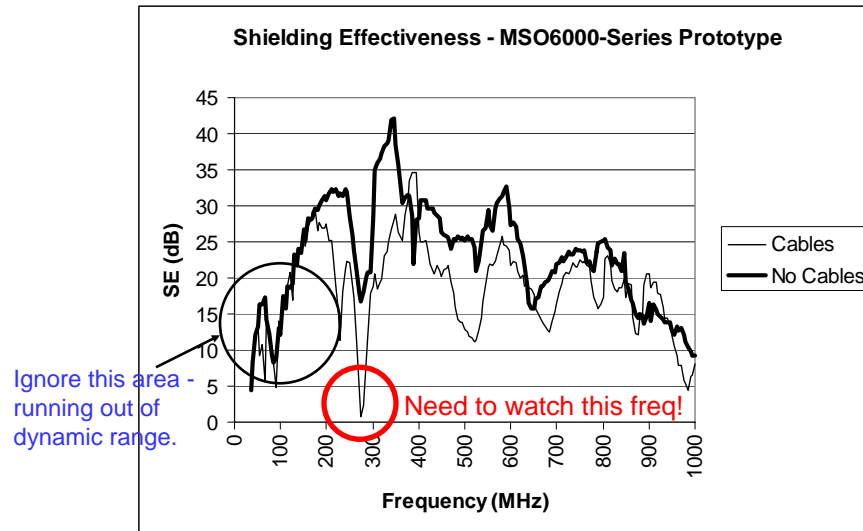
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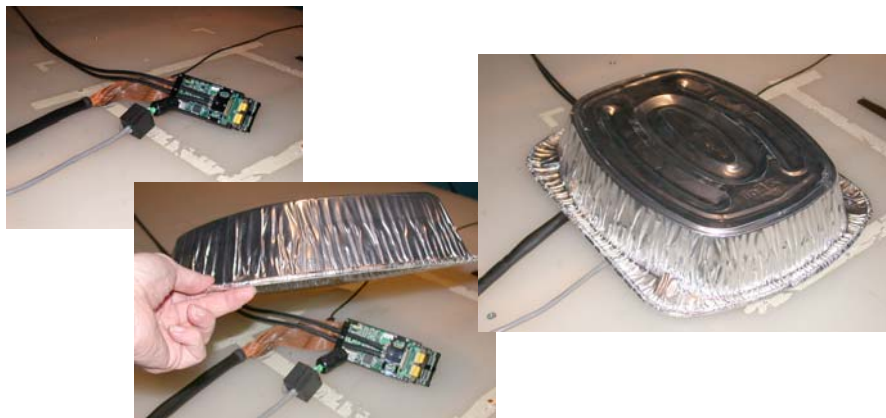
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## Shielding Effectiveness Plot Is The Difference!

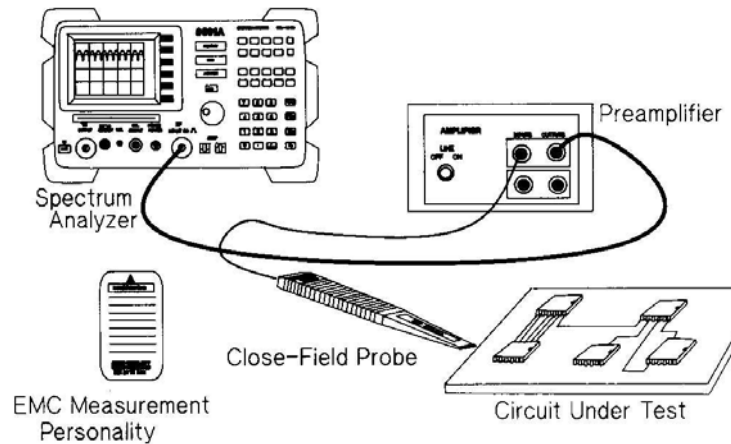


## Use of a Basting Pan To Isolate Emissions From Product or Cables



## Typical EMI Diagnostic Setup

### EMI Diagnostic Measurement Setup



Wilcox, A Design Process for Achieving Electromagnetic Compatibility, Compliance Engineering

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## Examples Of Home Made Loop (H-Field) Probes



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## Constructing a simple loop probe

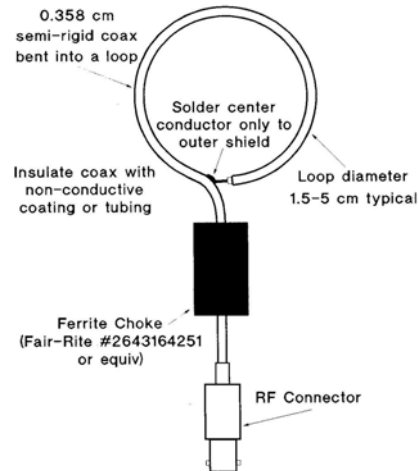


Figure 3. Simple, easy-to-make magnetic field probe.

Roleson, Finding EMI Resonances in Structures, EMC Test & Design, Jan/Feb 1992

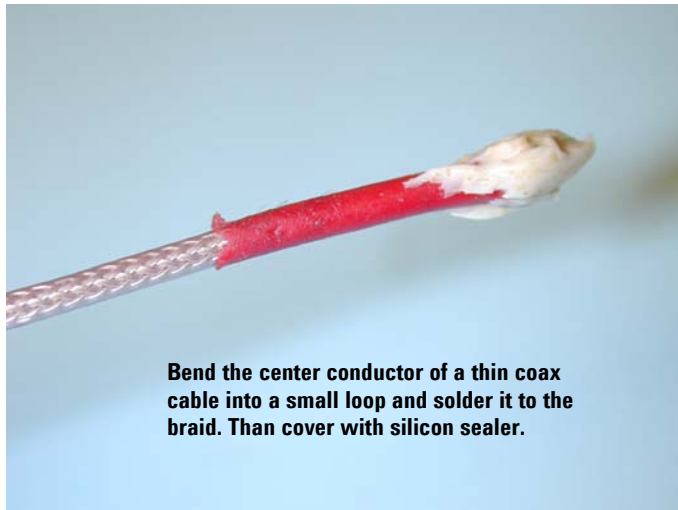
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## "Mini" loop probe



**Bend the center conductor of a thin coax cable into a small loop and solder it to the braid. Then cover with silicon sealer.**

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## Commercial Loop Probes

Commercial probes are available from several sources:

Beehive Electronics probes pictured...

[www.beehive-electronics.com](http://www.beehive-electronics.com)

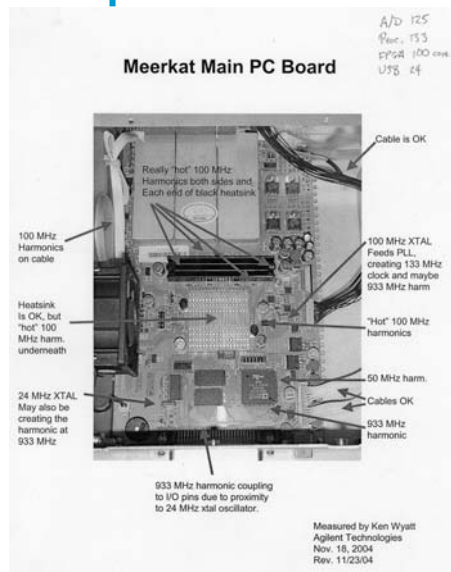
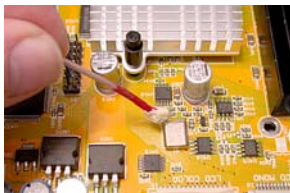


## Mapping Of PC Board "Hot Spots"

$\frac{1}{2}$ " Magnetic field probe for course measurements



"Micro" magnetic field probe for fine measurements



## Examples of current probes



These may be used to measure high-frequency (common-mode) currents in cables

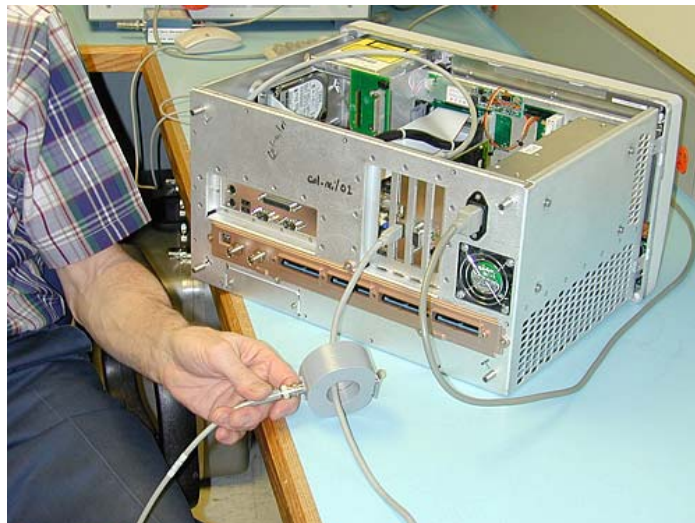
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## Using A Current Probe To Measure Cable Common-Mode Currents



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## Current Probe Transfer Impedance

Rather than carrying out a precise calculation, it is sufficient to measure the voltage with a known current and frequency passing through the probe.

This measurement is usually expressed as “transfer impedance” ( $Z_T$ ).

$$Z_T = \frac{\hat{V}}{\hat{I}}$$

Or, expressed in dB:

$$|Z_T|_{dB\Omega} = |\hat{V}|_{dB\mu V} - |\hat{I}|_{dB\mu A}$$

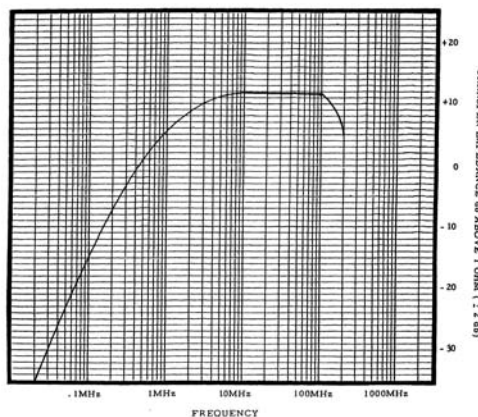


FIGURE 8.10 A typical measured current probe transfer impedance (courtesy of Fischer Custom Communications, Inc.)

## Application Of The Current Probe - Example

For example, consider the problem of determining the level of probe voltage that will correspond to a CM current on a cable that would just meet the radiated emission regulatory limit.

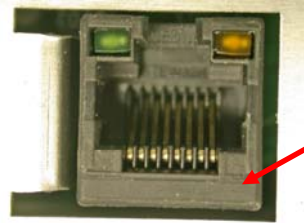
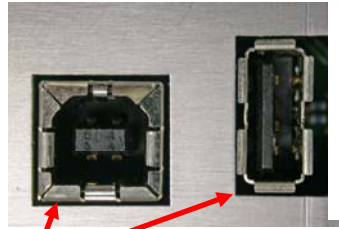
Clamping the probe around a cable and lumping the net CM current into one wire of length  $L$  gives the net radiated emission a distance  $d$  away. Note we must divide Eq. 8.16 by 2, since that result was for *two* wires carrying a current of  $I_C$ . Assuming FCC-B limit at 30 MHz (100  $\mu V/m$ ) and 1m cable.

$$|\hat{E}_C|_{\max} = 6.28 \times 10^{-7} \frac{|\hat{I}_{C,net}| f \mathcal{L}}{d} \quad (8.21)$$

$$\begin{aligned} |\hat{V}_{SA}|_{dB\mu V} &= |\hat{I}|_{dB\mu A} + |Z_T|_{dB\Omega} \\ &= 24 \text{ dB}\mu A + 15 \text{ dB}\Omega \\ &= 39 \text{ dB}\mu V \\ &\rightarrow 89 \mu V \end{aligned} \quad (8.22)$$

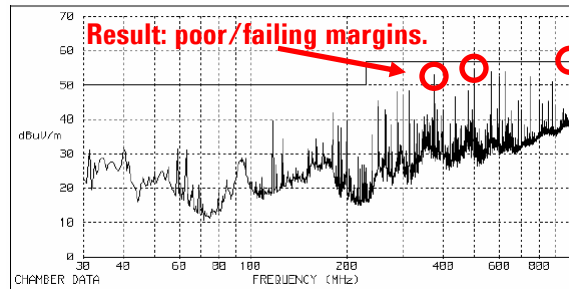
From: *Introduction to Electromagnetic Compatibility*, Paul

## Importance of I/O Connector Grounds



LAN conn  
needs gnd  
shell.

Note a lack of good  
connection between  
chassis enclosure and  
connector ground.



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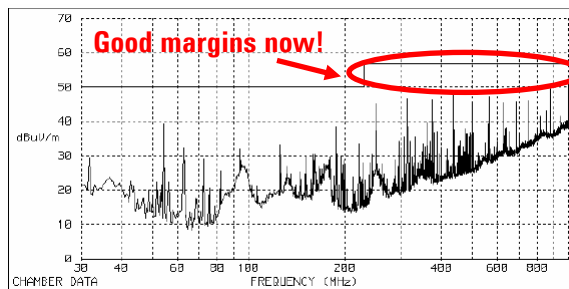
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## Results With I/O Cables Removed

I/O and video cables  
removed.

Ferrite on fan cable  
(reduced 1 GHz).

Margins are  
improved by 10+ dB.



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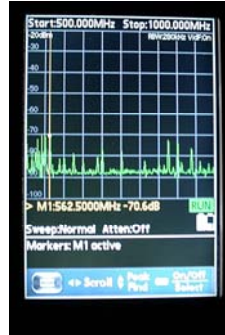
## Result After Simple Connection to Chassis



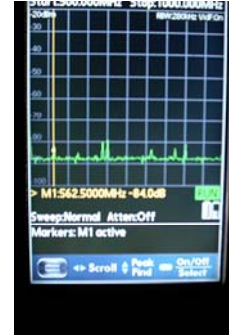
### **Test setup:**

**Current probe on USB cable.  
Connection between connector  
ground shell and chassis  
enclosure made with  
screwdriver blade.**

Looking from 500 to 1000 MHz



**Before**



**After**

**Some harmonics dropped by 10-15 dB!**

## Ferrite Chokes Block Common-Mode Currents

**Often used on keyboard,  
mouse or video cables**

**Very useful for  
troubleshooting**

**Manufactures often  
provide free evaluation kits**

**Best used on low-Z cables**



## The Concept of the Image Plane

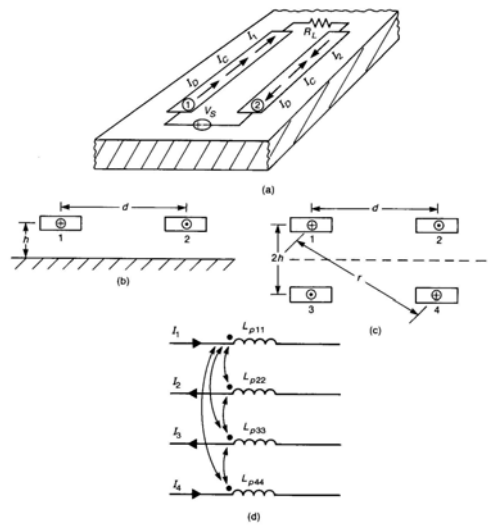


FIGURE 13.31 Use of an image plane to reduce the radiated emissions and ground drop of a PCB: (a) the board schematic; (b) the board cross section; (c) replacement of the image plane with images; (d) the partial inductance model.

## The Concept of the Image Plane

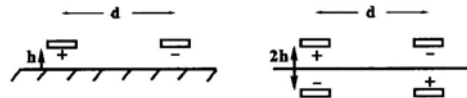


Figure 13 - Use of an image plane to cancel differential- and common-mode currents.

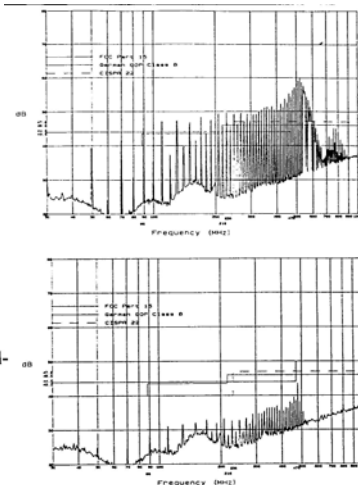


Figure 8. Radiated Emissions from PCB with Image Plane

Ott/Paul/German, Effect of an Image Plane on Printed Circuit Board Radiation, International Symposium on EMC, 1990

## The Concept of the Image Plane

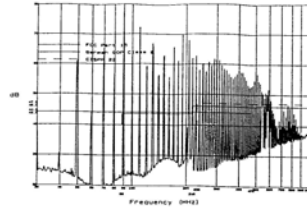


Figure 10. Radiated Emissions from PCB and Attached Wire

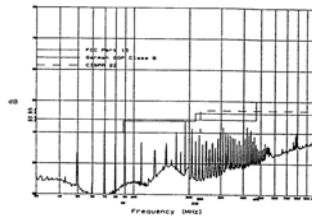


Figure 11. Radiated Emissions from PCB and Attached Wire with Image Plane

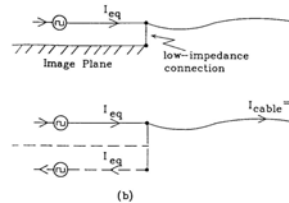
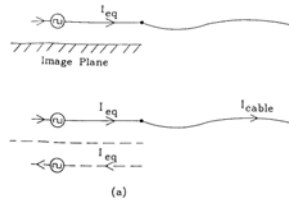


Figure 12. Connection between Image Plane and PCB with Attached Wire

CONCLUDING REMARKS

Ott/Paul/German, Effect of an Image Plane on Printed Circuit Board Radiation, International Symposium on EMC, 1990

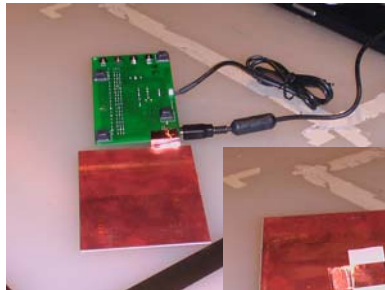
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## Use Of an Image Plane (IP) to Reduce Emissions



For troubleshooting purposes, attach IP near I/O connector ground and fold under PC board.



*Ultimately, for this project, we only needed a ferrite on the USB cable.*



An IP can reduce radiated emissions from PC boards by 8 to 15 dB. In practice, the IP can be the bottom layer of the PC board.

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## Line Cord Emissions

**If the line cord is suspected of emitting HF harmonics, insert an external line filter in series**

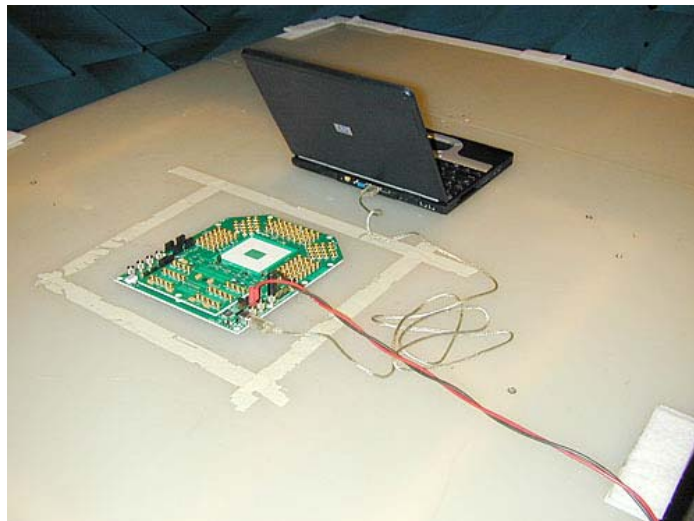
**If the emission level (or measured common-mode current) drops, then you need to design in better line filtering**

**An external filter may be made with an extra power line filter module and spare line cord**

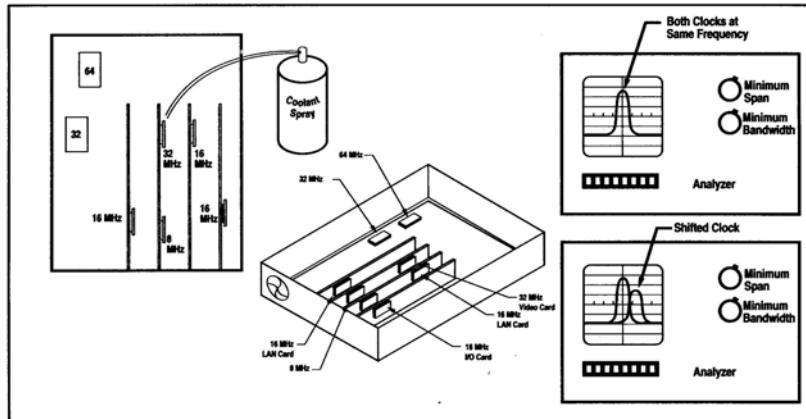
**Cut the cord down to minimal size and carefully solder the stripped ends to the filter, observing the correct connections. Wrap with electrical tape.**



## Testing A Bare PC Board For Radiated Emissions



## Use coolant spray to determine which oscillator is contributing the most to the harmonic of concern

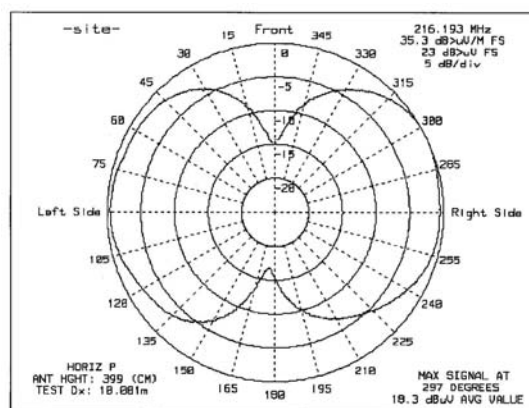


## Example Of A Polar Plot - Wide Lobes

Emissions are coming from the sides of the product.

Single- or double-lobed plot is typical behavior at the lower frequencies (<300 MHz).

Probably due to cable radiation.



Polar plot at 216 MHz. Shape indicates a half-wave dipole antenna pattern.

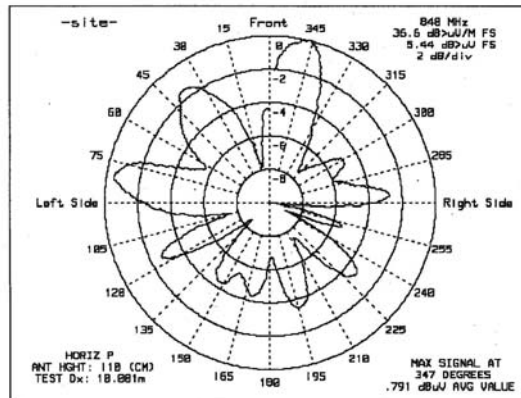


## Typical Polar Plot At Higher Frequencies - Narrow Lobes

Emissions are coming from all around the product

Typical behavior at the higher frequencies (>300 MHz)

Probably due to slot radiation.



Polar plot at 848 MHz. Pattern probably indicates slot radiation and multiple reflections.

## Using a loop probe to measure resonances

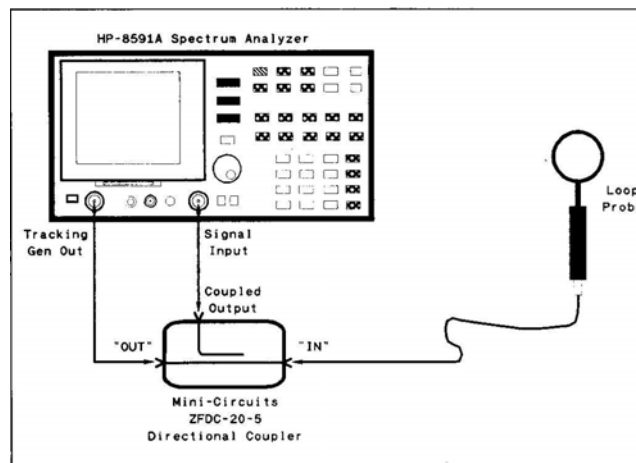
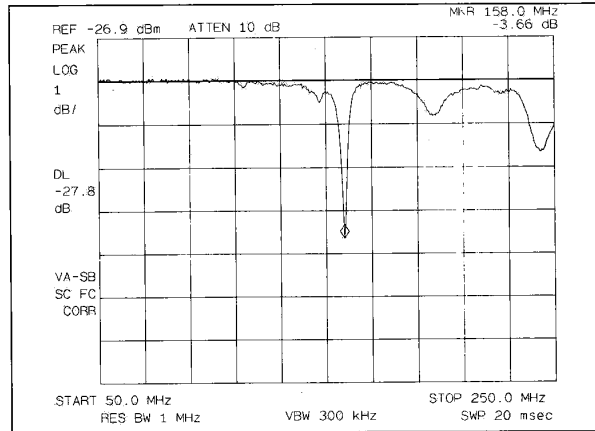


Figure 1. Setup for finding structural resonances.

## Resonance measurement



*Figure 2. Structural resonances are shown as dips in normalized trace on spectrum analyzer display.*

Roleson, Finding EMI Resonances in Structures, EMC Test & Design, Jan/Feb 1992

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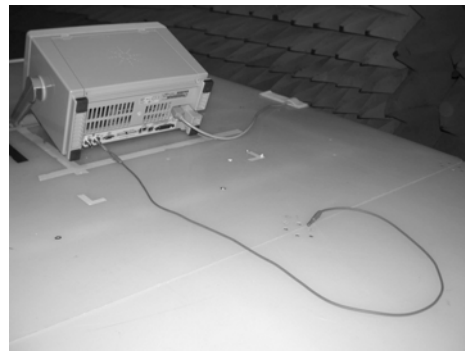
## External clip lead

**Useful for assessing proper signal return (or shield) connection back to enclosure**

**Connect 1m-long clip lead to various shield connection points on all I/O cable ports**

**Clamp a current probe around the cable (or measure the amount of radiated emissions)**

**If no current is detected or the clip lead has no effect on radiated emissions, that specific shield connection point is connected back to enclosure shielding OK**



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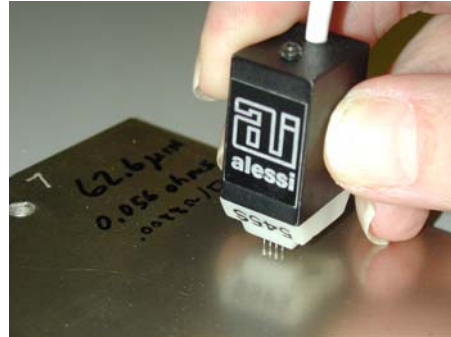
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## Plated shield resistivity measurement

Use of a “four-point” probe allows you to verify the sheet resistance, and hence the thickness of vapor-deposited (or plated) metallic shields.

A four-terminal DMM, such as the Agilent 34420A, is required.

By knowing the thickness, you can calculate the shielding effectiveness, given the manufacturer’s equation.



Alessi 545S probe shown

## Four Point Probe Method

*Assuming a 4-pin collinear array with equidistant pins and a “thin” sample.*

F2 = geometric correction factor (= 4.53 for probe  $\ll$  sample and a thin layer).

A “thin” conductive layer is defined as  $W \ll S$ .

Sheet Resistance ( $R_s$ ) =  $4.53 (V/I)$  (Ohms/square)

Resistivity ( $\rho$ ) =  $2 \pi s (V/I)$  (Ohm-cm, where  $s$  = point spacing in cm)

$t = \rho / R_s$  (cm)

## Use Of A Differential Probe To Assess Seam Integrity

**Connect a differential probe to a low-cost oscilloscope or spectrum analyzer**

**Place a probe tip on each side of an enclosure seam**

**If you measure an appreciable voltage difference, the seam connection is poor and may be a possible source of radiated emissions (*if seam length is greater than  $1/20^{\text{th}}$  of wavelength at frequency of interest*)**



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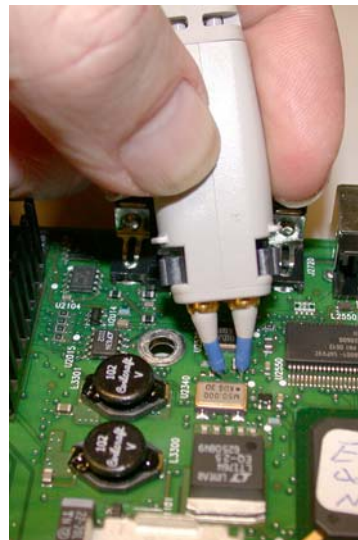
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## Use Of A Differential Probe To Assess PC Board "Noise"

**Connect a differential probe to a low-cost oscilloscope or spectrum analyzer**

**To measure ground plane noise, probe different points on the ground plane**

**To measure the effectivity of your bypass caps, probe from  $V_{\text{source}}$  to  $V_{\text{return}}$  at some distance from each high-risk IC.**



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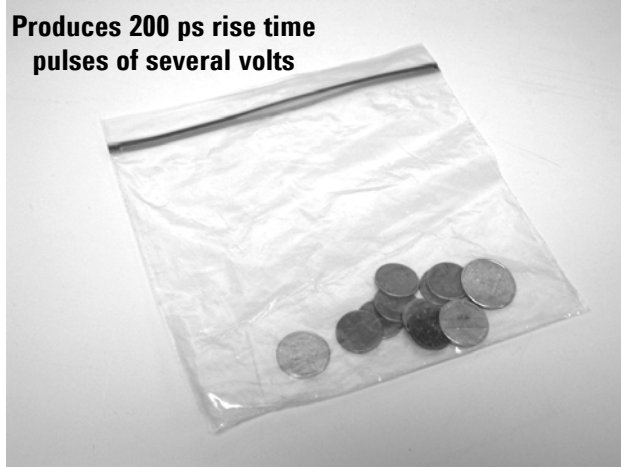


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## Simple ESD Source – Coins In ZipLok Bag (Simulates Pocket Change)

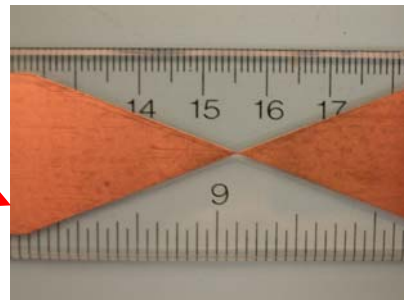
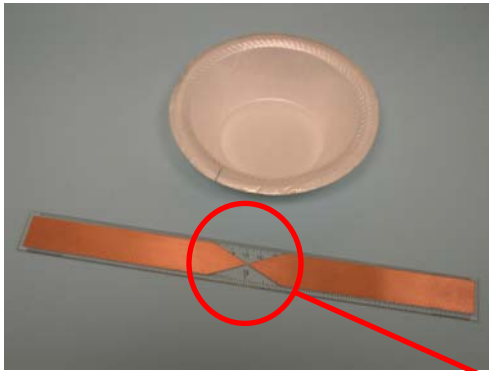
**Produces 200 ps rise time  
pulses of several volts**



Idea, courtesy of Doug Smith ([www.emcesd.com](http://www.emcesd.com))

## Simple ESD Source – Spark Gap Ruler

**Produces 200 - 500 ps rise time  
pulses of several volts**



Idea, courtesy of Doug Smith ([www.emcesd.com](http://www.emcesd.com))

## EMC Management Recommendations

- **Identify a regulatory point of contact within the design team**
- **Develop EMC design goals (6 dB margin for sample of five)**
- **Perform margin testing, rather than testing to limits**
- **EMC engineer is a part of the project management team**
- **Make early design reviews part of the product generation process**

